Search Notes

Application/Control No.		Applicant(s)/Patent under Reexamination	
10/509,120	YAMAKOSHI ET AL.		
Examiner	Art Unit	•	
Paul C. Martin	1657	11/23/07	

	SEARCHED		
Class	Subclass	Date	Examiner
n/a	n/a		РСМ
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
n/a	n/a		РСМ		

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
Inventor name search PALM/EAST: EPO, JPO, DERWENT, USPATFULL, USPGPUBS	11/23/2007	PCM
EAST: EPO, JPO, DERWENT, USPATFULL, USPGPUBS	11/23/2007	РСМ
STN: Indexed BIOSCIENCE cluster (74 databases)	11/23/2007	РСМ
Patentability conference, conferees: P. Martin, P. Leith Primary 1655 and J. Weber SPE 1657	11/20/2007	РСМ
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